



Application/Control No.	Applicant(s)/Patent under Reexamination
10/644,824	SHIROISHI, YOSHIHIRO
Examiner	Art Unit
Tianjie Chen	2656

SEARCHED					
Class	Subclass	Date	Examiner		
360	67				
	73.03				
	77.03				
	126				
369	13.02				
428	. 141				
	822	11/22/2005	TJ		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Report	11/22/2005	ΤJ		
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